

Special Issue

Deep Learning and Technology-Assisted Education

Message from the Guest Editors

In the ever-evolving field of education, fostering innovative approaches to enrich students' learning experiences stands as a pivotal imperative. The surge in machine learning (ML) technologies and the enthusiastic adoption of various neural network models in deep learning (DL), including recurrent, convolutional, LSTM networks, and groundbreaking transformer architectures, which possess the remarkable ability to generate human-level text, present challenging prospects in the field of education. These technologies hold the potential to boost the development and implementation of personalized, adaptable, and highly efficient educational experiences, finely tuned to address individual students' unique needs and levels of knowledge.

In this context, we invite prospective authors to submit articles covering, but not limited to, the following thematic areas related to technology-assisted education, where deep learning can serve as a valuable opportunity: Natural language processing
Development of intelligent tutoring systems
Detection of student participation and engagement
Promotion of critical thinking skills
Advances in lifelong learning

Guest Editors

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Deadline for manuscript submissions

closed (15 March 2024)



Applied Sciences

an Open Access Journal
by MDPI

Impact Factor 2.5
CiteScore 5.5



mdpi.com/si/184823

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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